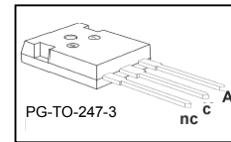


Fast Switching EmCon Diode

**Features:**

- 600 V EmCon technology
- Fast recovery
- Soft switching
- Low reverse recovery charge
- Low forward voltage
- 175 °C junction operating temperature
- Easy paralleling
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models:  
<http://www.infineon.com/emcon/>



**Applications:**

- Welding
- Motor drives

| Type      | $V_{RRM}$ | $I_F$ | $V_{F, T_J=25^\circ C}$ | $T_{j,max}$ | Marking | Package     |
|-----------|-----------|-------|-------------------------|-------------|---------|-------------|
| IDW100E60 | 600V      | 100A  | 1.65V                   | 175°C       | D100E60 | PG-TO-247-3 |

**Maximum Ratings**

| Parameter  | Symbol           | Value      | Unit |
|--|------------------|------------|------|
| Repetitive peak reverse voltage                                | $V_{RRM}$        | 600        | V    |
| Continuous forward current                                     | $I_F$            |            | A    |
| $T_C = 25^\circ C$   |                  | 150        |      |
| $T_C = 90^\circ C$   |                  | 104        |      |
| $T_C = 100^\circ C$  |                  | 96         |      |
| Surge non repetitive forward current                           | $I_{FSM}$        | 400        | A    |
| $T_C = 25^\circ C, t_p = 10 \text{ ms, sine halfwave}$         |                  |            |      |
| Maximum repetitive forward current                             | $I_{FRM}$        | 300        | A    |
| $T_C = 25^\circ C, t_p \text{ limited by } t_{j,max}, D = 0.5$ |                  |            |      |
| Power dissipation  | $P_{tot}$        |            | W    |
| $T_C = 25^\circ C$   |                  | 375        |      |
| $T_C = 90^\circ C$   |                  | 212        |      |
| $T_C = 100^\circ C$  |                  | 198        |      |
| Operating junction and storage temperature                     | $T_{j, T_{stg}}$ | -55...+175 | °C   |
| Soldering temperature  | $T_S$            | 260        | °C   |
| 1.6mm (0.063 in.) from case for 10 s                           |                  |            |      |

**Thermal Resistance**

| Parameter                              | Symbol     | Conditions | Max. Value | Unit |
|--|------------|------------|------------|------|
| <b>Characteristic</b>                  |            |            |            |      |
| Thermal resistance, junction – case    | $R_{thJC}$ |            | 0.40       | K/W  |
| Thermal resistance, junction – ambient | $R_{thJA}$ |            | 40         |      |

**Electrical Characteristic, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified**

| Parameter | Symbol | Conditions | Value |      |      | Unit |
|-----------|--------|------------|-------|------|------|------|
|           |        |            | min.  | typ. | max. |      |

**Static Characteristic**

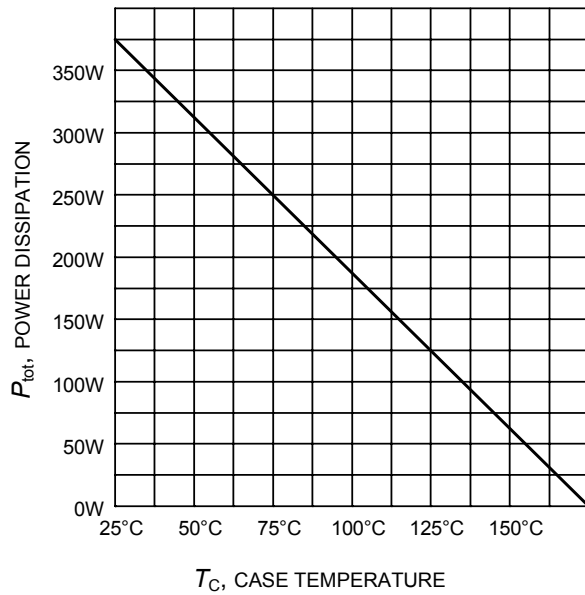
|                                     |           |  |        |              |            |               |
|-------------------------------------|-----------|--|--------|--------------|------------|---------------|
| Collector-emitter breakdown voltage | $V_{RRM}$ | $I_R = 0.25\text{mA}$  | 600    | -            | -          | V             |
| Diode forward voltage               | $V_F$     | $I_F = 100\text{A}$<br>$T_j = 25^\circ\text{C}$<br>$T_j = 175^\circ\text{C}$ | -<br>- | 1.65<br>1.65 | 2.0<br>-   |               |
| Reverse leakage current             | $I_R$     | $V_R = 600\text{V}$<br>$T_j = 25^\circ\text{C}$<br>$T_j = 175^\circ\text{C}$ | -<br>- | -<br>-       | 40<br>1000 | $\mu\text{A}$ |

**Dynamic Electrical Characteristics**

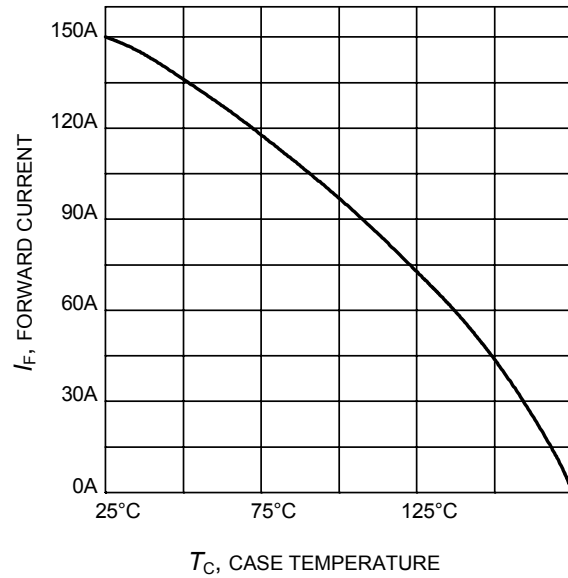
|  |              |                                      |   |      |   |                        |
|--|--------------|--------------------------------------|---|------|---|------------------------|
| Diode reverse recovery time                                      | $t_{rr}$     | $T_j = 25^\circ\text{C}$             | - | 120  | - | ns                     |
| Diode reverse recovery charge                                    | $Q_{rr}$     | $V_R = 400\text{V}$ ,                | - | 3.6  | - | $\mu\text{C}$          |
| Diode peak reverse recovery current                              | $I_{rr}$     | $I_F = 100\text{A}$ ,                | - | 49.5 | - | A                      |
| Diode peak rate of fall of reverse recovery current during $t_b$ | $dl_{rr}/dt$ | $dl_F/dt = 1200\text{A}/\mu\text{s}$ | - | 750  | - | $\text{A}/\mu\text{s}$ |

|  |              |                                      |   |      |   |                        |
|--|--------------|--------------------------------------|---|------|---|------------------------|
| Diode reverse recovery time                                      | $t_{rr}$     | $T_j = 125^\circ\text{C}$            | - | 168  | - | ns                     |
| Diode reverse recovery charge                                    | $Q_{rrm}$    | $V_R = 400\text{V}$ ,                | - | 5.8  | - | $\mu\text{C}$          |
| Diode peak reverse recovery current                              | $I_{rr}$     | $I_F = 100\text{A}$ ,                | - | 61.6 | - | A                      |
| Diode peak rate of fall of reverse recovery current during $t_b$ | $dl_{rr}/dt$ | $dl_F/dt = 1200\text{A}/\mu\text{s}$ | - | 705  | - | $\text{A}/\mu\text{s}$ |

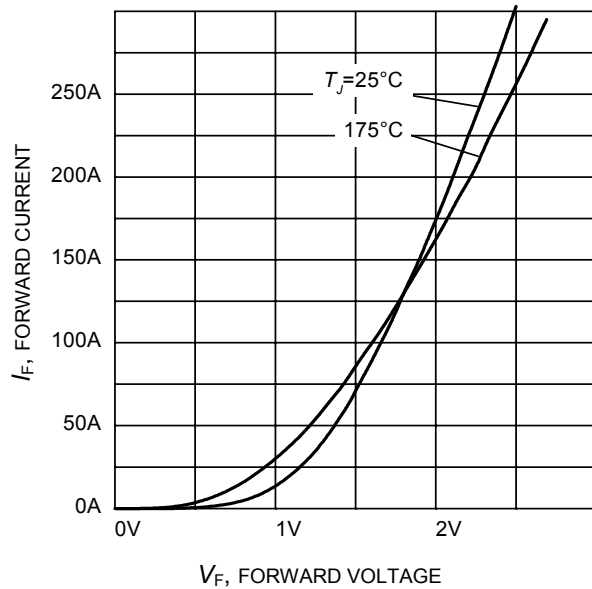
|  |              |                                      |   |      |   |                        |
|--|--------------|--------------------------------------|---|------|---|------------------------|
| Diode reverse recovery time                                      | $t_{rr}$     | $T_j = 175^\circ\text{C}$            | - | 200  | - | ns                     |
| Diode reverse recovery charge                                    | $Q_{rrm}$    | $V_R = 400\text{V}$ ,                | - | 7.8  | - | $\mu\text{C}$          |
| Diode peak reverse recovery current                              | $I_{rr}$     | $I_F = 100\text{A}$ ,                | - | 67.0 | - | A                      |
| Diode peak rate of fall of reverse recovery current during $t_b$ | $dl_{rr}/dt$ | $dl_F/dt = 1200\text{A}/\mu\text{s}$ | - | 650  | - | $\text{A}/\mu\text{s}$ |



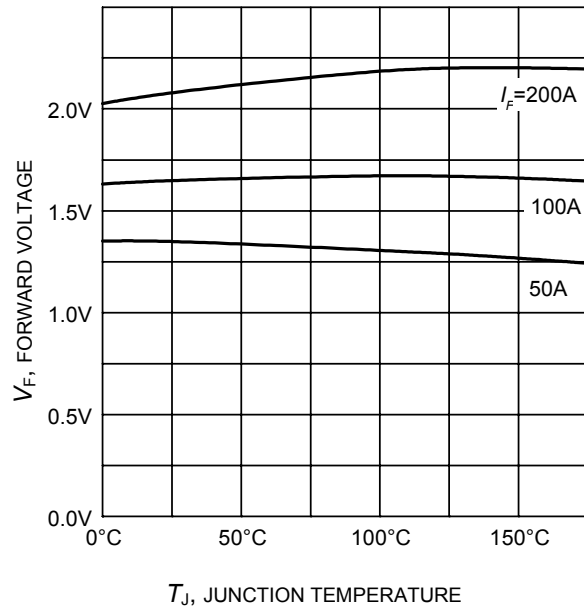
**Figure 1. Power dissipation as a function of case temperature**  
( $T_j \leq 175^\circ\text{C}$ )



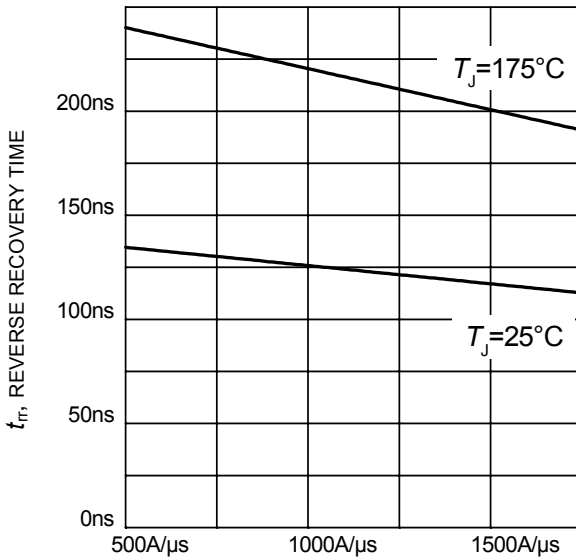
**Figure 2. Diode forward current as a function of case temperature**  
( $T_j \leq 175^\circ\text{C}$ )



**Figure 3. Typical diode forward current as a function of forward voltage**

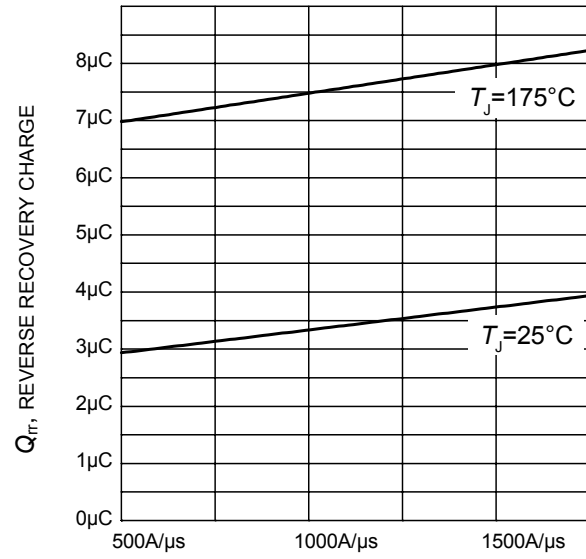


**Figure 4. Typical diode forward voltage as a function of junction temperature**



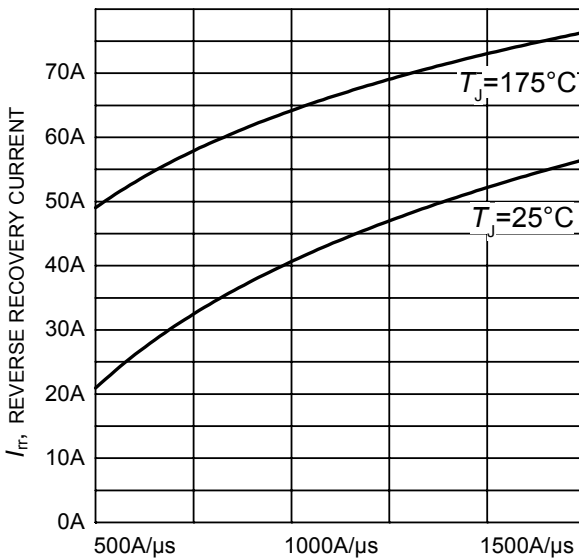
$di_f/dt$ , DIODE CURRENT SLOPE

**Figure 5. Typical reverse recovery time as a function of diode current slope**  
 ( $V_R=400V$ ,  $I_F=100A$ ,  
 Dynamic test circuit in Figure E)



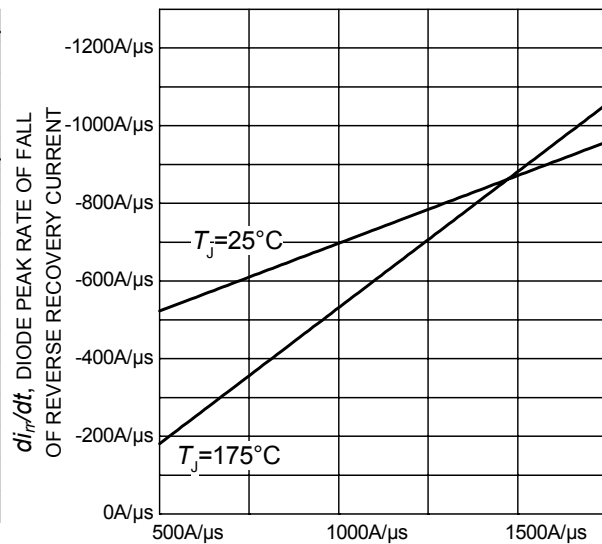
$di_f/dt$ , DIODE CURRENT SLOPE

**Figure 6. Typical reverse recovery charge as a function of diode current slope**  
 ( $V_R = 400V$ ,  $I_F = 100A$ ,  
 Dynamic test circuit in Figure E)



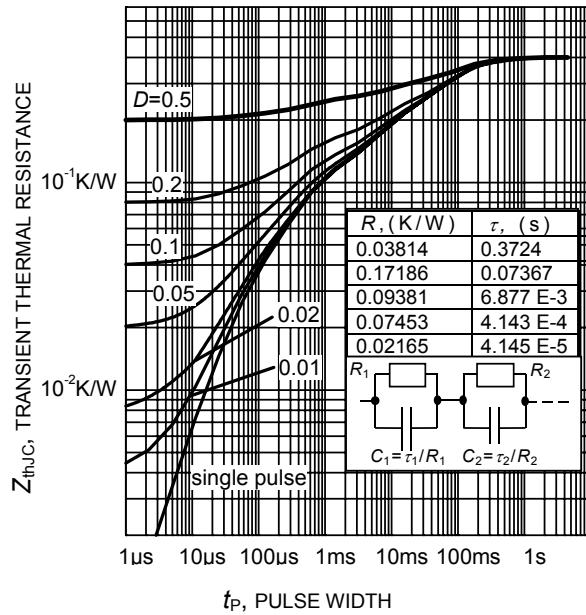
$di_f/dt$ , DIODE CURRENT SLOPE

**Figure 7. Typical reverse recovery current as a function of diode current slope**  
 ( $V_R = 400V$ ,  $I_F = 100A$ ,  
 Dynamic test circuit in Figure E)



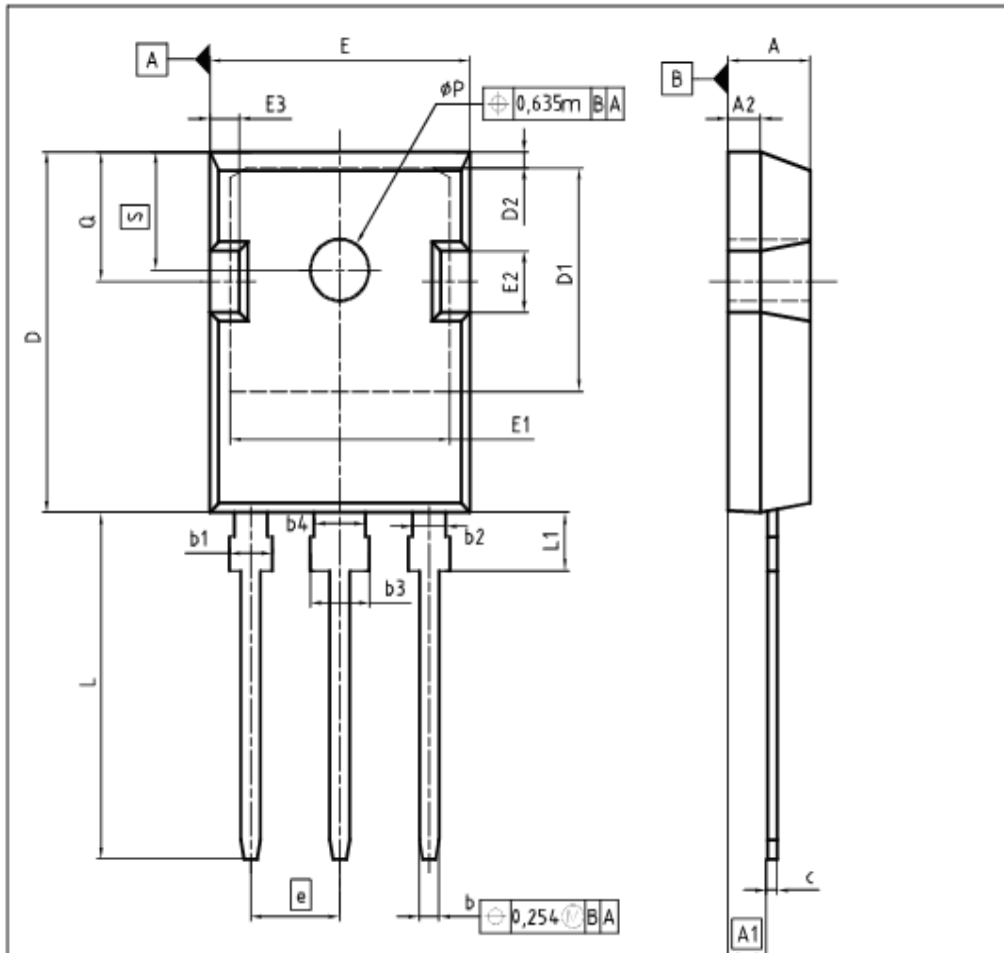
$di_f/dt$ , DIODE CURRENT SLOPE

**Figure 8. Typical diode peak rate of fall of reverse recovery current as a function of diode current slope**  
 ( $V_R=400V$ ,  $I_F=100A$ ,  
 Dynamic test circuit in Figure E)



**Figure 9. Diode transient thermal impedance as a function of pulse width**  
 ( $D=t_p/T$ )

T0247-3



| DIM      | MILLIMETERS |       | INCHES |       |
|----------|-------------|-------|--------|-------|
|          | MIN         | MAX   | MIN    | MAX   |
| A        | 4.83        | 5.21  | 0.190  | 0.205 |
| A1       | 2.27        | 2.54  | 0.089  | 0.100 |
| A2       | 1.85        | 2.16  | 0.073  | 0.085 |
| b        | 1.07        | 1.33  | 0.042  | 0.052 |
| b1       | 1.90        | 2.41  | 0.075  | 0.095 |
| b2       | 1.90        | 2.16  | 0.075  | 0.085 |
| b3       | 2.87        | 3.38  | 0.113  | 0.133 |
| b4       | 2.87        | 3.13  | 0.113  | 0.123 |
| c        | 0.55        | 0.68  | 0.022  | 0.027 |
| D        | 20.80       | 21.10 | 0.819  | 0.831 |
| D1       | 16.25       | 17.65 | 0.640  | 0.695 |
| D2       | 0.95        | 1.35  | 0.037  | 0.053 |
| E        | 15.70       | 16.13 | 0.618  | 0.635 |
| E1       | 13.10       | 14.15 | 0.516  | 0.557 |
| E2       | 3.68        | 5.10  | 0.145  | 0.201 |
| E3       | 1.00        | 2.60  | 0.039  | 0.102 |
| e        | 5.44        |       | 0.214  |       |
| N        | 3           |       | 3      |       |
| L        | 19.80       | 20.32 | 0.780  | 0.800 |
| L1       | 4.10        | 4.47  | 0.161  | 0.176 |
| $\phi P$ | 3.50        | 3.70  | 0.138  | 0.146 |
| Q        | 5.49        | 6.00  | 0.216  | 0.236 |
| S        | 6.04        | 6.30  | 0.238  | 0.248 |

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